

**CURSO DE PÓS-GRADUAÇÃO EM  
ENGENHARIA E TECNOLOGIA ESPACIAIS**

**ÁREA DE CONCENTRAÇÃO EM  
CIÊNCIA E TECNOLOGIA DE MATERIAIS E SENSORES**

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**Coordenadoria Acadêmica do Curso**

Walter Abrahão dos Santos

**Coordenadoria Acadêmica da Área de Concentração**

Sergio Luiz Mineiro

**Docentes Permanentes**

Carina Barros Mello, Doutora, INPE, Brasil, 2011

Eduardo Abramof, Doutor, Univ. Johannes Kepler, Áustria, 1993

Evaldo José Corat, Doutor, ITA, Brasil, 1993

Maria do Carmo de Andrade Nono, Doutora, ITA, Brasil, 1990

Mario Ueda, Doutor, Cornell, E.U.A, 1986

Maurício Ribeiro Baldan, Doutor, ITA, Brasil, 1997

Neidenei Gomes Ferreira, Doutora, UNICAMP, Brasil, 1994

Paulo Henrique de Oliveira Rappl, Doutor, ITA, Brasil, 1998

Rogério de Moraes Oliveira, Doutor, INPE, Brasil, 2004

**Docentes Colaboradores**

Luiz Ângelo Berni, Doutor, UNICAMP, Brasil, 1996

Sergio Luiz Mineiro, doutor, INPE, Brasil, 2007

Patrícia Regina Pereira Barreto, Doutora, ITA. Brasil, 1998

Vladimir Jesus Trava-Aioldi, Doutor, ITA, Brasil, 1986

Waldeir Amaral Vilela, Doutor, INPE, Brasil, 2010

**Colaboradores Especiais**

Andrea Boldarini Couto, Doutora, UFSCar, Brasil, 2005

Chen Ying An, Doutor, ITA, Brasil, 1998

Eder Paduan Alves, Doutor, INPE, Brasil, 2016

Francisco Piorino Neto, Doutor, FAENQUIL, Brasil, 2000

João Marcos Kruszynski de Assis, Doutor, INPE, Brasil, 2014

Rafael Cardoso Toledo, Doutor, INPE, Brasil, 2013

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**1º Período Letivo**

***Obrigatória para o Mestrado***

CMS-200-4	Materials Science I
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***Obrigatória para o Mestrado e o Doutorado***

CMS-203-1	Seminars I
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***Eletiva***

CMS-205-4	Mathematical methods applied to materials science
CMS-421-4	Introduction to microscopy of materials

**2º Período Letivo**

***Obrigatória para o Mestrado e o Doutorado***

CMS-204-1	Seminars II
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***Obrigatórias adicionais para o Mestrado (\*)***

CMS-207-4	Experimental techniques in materials science I
CMS-206-4	Elements from Theory of errors and statistical treatment of data
CMS-306-4	Physics of Ceramics
CMS-307-4	Physics and chemistry of solid surfaces
CMS-337-4	Introduction to nanoscience and nanotechnology materials

(\*) O aluno de mestrado deverá cursar uma disciplina (total de 4 créditos) desta lista, que será considerada obrigatória. As demais disciplinas cursadas passarão a ser consideradas como eletivas.

***Eletivas***

CMS-300-4	Quantum mechanics
CMS-405-4	Growth of CVD Diamond films
CMS-410-4	Plasma technology for surface treatment

### **3º Período Letivo e Seguintes**

#### ***Eletivas***

CMS-301-4	Solid state physics
CMS-308-4	Physics of Nanostructures
CMS-323-4	Silicon solar cells and radiation sensors: basic concepts, techniques of manufacture and characterization
CMS-329-4	Chemical kinetics
CMS-336-4	Mechanical characterization of materials
CMS-347-4	Introduction to Radiometry
CMS-403-4	Surfaces and Interfaces of materials: Modification and characterization
CMS-404-4	Thin films technology
CMS-406-4	Porous Materials
CMS-407-4	Covalent ceramics and aerospace applications
CMS-409-4	Environmental sensors and control
CMS-419-4	Principles of electrochemistry
CMS-414-4	Processing and characterization of advanced ceramics
CMS-415-4	Processing and characterization of nanostructured ceramics
CMS-416-4	Nanoparticle powders: obtaining, characterization and applications
CMS-417-4	Nanostructured films: production, Characterization and applications
CMS-420-4	X-ray diffractometry for characterization of crystalline structure of materials
CMS-315-1	Special topics in science and physics of materials I (*)
CMS-316-2	Special topics in science and physics of materials II (*)
CMS-339-3	Special topics in science and physics of materials III (*)
CMS-340-4	Special topics in science and physics of materials IV (*)
CMS-317-1	Special topics in materials processing I (*)
CMS-318-2	Special topics in materials processing II (*)
CMS-341-3	Special topics in materials processing III (*)
CMS-342-4	Special topics in materials processing IV (*)
CMS-319-1	Special topics in materials characterization techniques I (*)
CMS-320-2	Special topics in materials characterization techniques II (*)
CMS-343-3	Special topics in materials characterization techniques III (*)
CMS-344-4	Special topics in materials characterization techniques IV (*)
CMS-324-4	Research in physics of materials I (*)
CMS-325-4	Research in physics of materials II (*)
CMS-326-4	Research in physics of materials III (*)
CMS-330-4	Research in physics of materials IV (*)
CMS-331-4	Research in physics of materials V (*)
CMS-332-4	Research in physics of materials VI (*)
CMS-345-4	Research in physics of materials VII (*)
CMS-321-4	Research in science and technology of materials I (*)
CMS-327-4	Research in science and technology of materials II (*)
CMS-328-4	Research in science and technology of materials III (*)
CMS-333-4	Research in science and technology of materials IV (*)
CMS-334-4	Research in science and technology of materials V (*)
CMS-335-4	Research in science and technology of materials VI (*)
CMS-346-4	Research in science and technology of materials VII (*)

(\*) Disciplinas com ementas específicas para cada assunto

## **EMENTAS DAS DISCIPLINAS DA ÁREA DE CONCENTRAÇÃO EM CIÊNCIA E TECNOLOGIA DE MATERIAIS E SENSORES**

### **CMS-200-4 Materials Science I**

#### **Obrigatória para o Mestrado**

**Pré-requisito:** não há

**Carga horária:** 60 horas

Atomic structures and interatomic bonds. Crystalline and non-crystalline structures of solids. Imperfections in solids. Atomic and Ionic mobility. Nucleation and development of microstructures. Phase equilibrium diagrams. Mechanical properties. Thermal properties. Electrical and dielectric properties. Magnetic properties. Optical properties.

#### **Bibliografia**

SHACKELFORD, J. F. Introduction to Materials Science for Engineers. MacMillan Publishing Company, new York, U.S.A., 1992

CALLISTER Jr., W. D. Materials Science and Engineering - An Introduction. John Wiley & Sons Inc., 3<sup>th</sup> edition, U.S.A., 1994

ORING, M. Engineering Materials Science. Academic Press, U.S.A., 1995

S. M. ALLEN and E. L. THOMAS, The Structure of Materials, Wiley, New York, 1999

KITTEL, C. Introduction to Solid State Physics. John Willey & Sons, Inc, New York, 1996.

### **CMS-203-1 Seminars I**

#### **Obrigatória para o Mestrado e o Doutorado**

**Pré-requisito:** não há

**Carga horária:** 15 horas

Issues of interest in lectures given by professors of the graduate program and guests.

### **CMS-204-1 Seminars II**

#### **Obrigatória para o Mestrado e o Doutorado**

**Pré-requisito:** não há

**Carga horária:** 15 horas

Issues of interest in lectures given by professors of the graduate program and guests.

### **CMS-205-4 Mathematical methods applied to materials science**

#### **Eletiva**

**Pré-requisito:** não há

**Carga horária:** 60 horas

Introduction to derivatives. Rules of derivation. Maxima and minima. Closed intervals minimum. Applications involving derivatives. Introduction to integral. Techniques of integration. Double integration. Polar coordinates. Ordinary differential equations, classification, separation solution. Vectors and bases. Scalar and vector fields. Gradient, divergence and curl in orthogonal coordinates, representation, cylindrical and spherical. Introduction to computational tools: Mathematica and Maple.

#### **Bibliografia**

BUTKOV, E. Física Matemática. Guanabara Dois, Rio de Janeiro, RJ, 1978.

ARFKEN, G. Mathematical Methods for Physicists. Academic Press, New York, 1970.

<b>CMS-206-4</b>	<b>Elements from the Theory of errors and statistical treatment of data</b>
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**Eletiva**

**Pré-requisito:** não há

**Carga horária:** 60 horas

Elements from the Theory of Errors. Physical quantity and significant figures.

True value, uncertainties, types of errors and source of errors. Population, sampling, frequency distribution and histogram. Probability distribution and types of distribution curves. Expected value, standard deviation, variance, standard deviation and chi-squared ( $\chi^2$ ). Error propagation, variances and covariances.

Statistical treatment of data. Maximum-likelihood estimation (MLE - maximum likelihood method). Method of least squares. Adjustment of curves using linear function. Linear and polynomial regression. Evaluation of the quality of an adjustment.

**Bibliografia**

VUOLO, J. H. Fundamentos da Teoria de Erros. Edgard Blücher Ltda, São Paulo, 1992.

HELENE, O. A. M.; VANIN, V. R. Tratamento Estatístico de Dados em Física Experimental. Edgard Blücher Ltda, São Paulo, 1981.

BEVINGTON, P. R. Data Reduction and Error Analysis for the Physical Sciences. McGraw-Hill Inc., 1969.

<b>CMS-207-4</b>	<b>Experimental techniques in materials science I</b>
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**Obrigatória adicional**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

X-ray diffraction techniques. Raman spectroscopy. Scanning electron microscopy and EDS analysis. X-ray photoelectron spectroscopy. Mechanical properties of materials.

**Bibliografia**

KITTEL, C. Introduction to Solid State Physics. John Wiley & Sons, Inc, New York, 1992.

ATKINS, P.W. Physical Chemistry. Oxford University Press, Oxford, UK, 2001.

GOLDSTEIN, J.I. et al. Scanning Electron Microscopy and X-Ray Microanalysis. Plenum Press, New York, 2nd. Ed., 1992.

CHEESCOE, D. AND; GOODSHEW, J. The Operation of Transmission and Scanning Electron Microscopes. Oxford Science Publications, Royal Microscopical Society, 1990.

CHEN, J. Introduction to Scanning Tunneling Microscopy, Oxford Series in Optical and Image Sciences 4. Oxford University Press, Oxford, UK, 1993.

CULLITY, D. B. Elements of X-Ray Diffraction. 2nd. Edition. Addison-Wesley, Reading-MA, 1978.

BERTIN, E.P. Introduction to X-Ray Spectrometric Analysis. Plenum Press, New York, 1978.

JENKINS, R. et al. Quantitative X-Ray Spectrometry. Marcel Dekker, Inc., New York, 1981.

Metals Handbook, 9th Edition, Vol.10, Materials Characterization. American Society for Metals, 1986.

Fairley, N. CasaXPS Manual - Introduction to XPS and AES. Casa Software Ltd, 2009.

MENDES, F. M. T. Introdução à Técnica de Espectroscopia Fotoeletrônica por Raios X (XPS). Synergia Editora, 2011.

Catálogos de equipamentos.

Artigos de periódicos especializados.

## CMS-300-4 | Quantum mechanics

### Obrigatória adicional

**Pré-requisito:** não há

**Carga horária:** 60 horas

The limits of classical physics. Wave packets and uncertainty relations. The Schrödinger equation. Eigenfunctions and eigenvalues. One-dimensional potentials. Vector spaces and operators. Many particle systems. Schrödinger equation in 3 dimensions and the hydrogen atom. Spin. Time-independent perturbation theory. Atoms and the periodic table. Molecules. Time-dependent perturbation theory. Polarizability and dielectric function.

### Bibliografia

- COHEN-TENNOUDJI, C.; DIU, B.; LAOË, F. Quantum Mechanics. John Wiley & Sons, Inc, New York, 1977.  
GASIOROWICZ, S. Quantum Physics. 2<sup>a</sup> edition, Wiley & Sons, 1996.  
McQUARRIE, D. A. Quantum Chemistry. University Science Books, 1983.  
McQUARRIE, D. A.; SIMON, J. D. Simon; CHOI, Physical Chemistry: A Molecular Approach. University Science Books, 1997.  
LEVINE, I. Quantum Chemistry. Prentice Hall, 1996.

## CMS-301-4 | Solid State Physics

### Eletiva

**Pré-requisito:** não há

**Carga horária:** 60 horas

Bravais lattice, reciprocal lattice, crystalline structure, and crystal diffraction, network vibrations: phonons, electronic levels in a periodic potential: Bloch's theorem, energy bands, Fermi surface, Brillouin zones, model of Drude and Sommerfeld, classic model of driving, dielectric properties, homogeneous and non-homogeneous semiconductors, magnetic properties: diamagnetism, Paramagnetism and ferromagnetism.

### Bibliografia

- KITTEL, C. Introduction to Solid State Physics. John Wiley & Sons, Inc, New York, 1967.  
ASHCROFT, N. W.; MERMIN, N. D. Solid State Physics. Saunders College Publishing, NY, 1976.  
Artigos selecionados de publicações especializadas.

## CMS-306-4 | Physics of ceramics

### Obrigatória adicional

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Characteristics of the solid ceramics. Crystalline structures. Glass structures. Structural imperfections. Surfaces, interfaces and grain boundary. Atomic mobility. Phase equilibrium. Development of the microstructure in Ceramics: reactions with and between solids, grain growth, sintering and glazing.

### Bibliografia

- CHIANG, Y. M.; BIRNIE, D. P.; KINGERY, W. D. Physical Ceramics: Principles for Ceramic Science and Engineering. Wiley & Sons, New York, 1996.  
KINGERY, W. D. Introduction to Ceramics. et al., 2<sup>nd</sup> edition, Wiley & sons, New York, 1976.  
RING, T.A. Fundamentals of Ceramic Powder Processing and Synthesis. Academic Press, New York, 1995.  
TURTON, R. J. The Physics of Solids, Oxford University Press, England, 2000.

Artigos selecionados de publicações específicas.

#### **CMS-307-4 | Physical and chemical surfaces of solids**

##### **Obrigatória adicional**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Scientific and technological importance. Atomic structure on the surface of solids and liquids. Electronic structure on the surface. Surface tension. Thermodynamics of systems with a component. Thermodynamics of multicomponent systems. Surface mobility. Physical Adsorption. Adsorption chemistry. Modification of surface reactivity. Electron-surface interactions. Ion-surface interactions. Phonon-surface interactions. Internal surfaces: interfaces. Types of interfaces. Mechanisms for the formation of defined, diluted and multiple interfaces.

##### **Bibliografia**

HUDSON, J. B. Surface Science: An Introduction. Pergamon Press Inc., New York, 1994.

TURTON, R. J. The Physics of Solids, Oxford University Press, England, 2000.

PRUTTON, M. Introduction to Surface Physics, Oxford University Press, England, 1996.

LUTH, H. Surfaces and Interfaces of Solid Materials. Pergamon Press, New York, 1998.

SUTTON, A. P.; BALLUFFI, R. W. Interfaces in Crystalline Materials, Oxford University Press, Oxford, 1996.

OHRING, M. The Materials Science of Thin Films. Academic Press, USA, 1991.

ADAMSON, A.W. Physical Chemistry of Surfaces. John Wiley & Sons, U.S.A., 1967.

S. M. ALLEN and E. L. THOMAS, The Structure of Materials, Wiley, New York, 1999.

CALLISTER Jr., W. D. Materials Science and Engineering - An Introduction. John Wiley & Sons Inc., 3<sup>th</sup> edition, U.S.A., 1994.

#### **CMS-308-4 | Physics of nanostructures**

##### **Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Nanometric scale, quantum confinement, mesoscopic phenomena, molecular nanostructures, electronic structure and optical and transport properties of superlattices, quantum wells, wires and dots, quantized Hall effect, spin-dependent properties, devices and new structures.

##### **Bibliografia**

FERRY, D. K.; GOODNIK, S. M. Transport in Nanostructures. Cambridge University Press, 1999.

BASTARD, G. Wave mechanics applied to semiconductor heterostructures. Les Éditions de Physique, France, 1990.

DATTA, S. Quantum Phenomena. Addison-Wesley Press, USA, 1989.

#### **CMS-323-4 | Silicon solar cells and radiation sensors: basic concepts, manufacturing techniques and characterization**

##### **Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Introduction: General aspects of solar energy. Solar energy conversion into thermal energy and electricity. Different types of solar cells. Key differences between solar-cells used for terrestrial and space applications. Solar spectrum. Solar Simulator. Silicon: Material considerations. Light absorption in silicon. Band diagram. Manufacturing processes: Obtaining and preparing the

blade itself. Formation of the n-p and p-n junction. Contacts and anti-reflective coating. Theory: p-n junction. Photovoltaic effect. current density vector J. Quantum efficiency. Characterization: Characteristic IxV in dark and under illumination. Equivalent circuit. Determination of resistance in series and parallel. Spectral response and quantum efficiency: measures of diffusion length and life time for minority carriers. Reflectivity: reflectivity speculate and diffuse. Layers anti-reflective coating texturing. Porous silicon. Basic concepts about radiation sensors. Calibration techniques and characterization of solar radiation sensors.

**Bibliografia:**

WORLD METEOROLOGICAL ORGANIZATION. Guide to Meteorological Instruments and Methods of Observation. 7<sup>a</sup>. s.l. : Chairperson, Publications Board, 2008. ISBN 978-92-63-10008-5.

MCCLUNNEY, W. R. Introduction to Radiometry and Photometry. Boston / London : Artech House, inc., 1994. ISBN 0-89006-678-7.

PARK, JOHN e MACKAY, STEVE. Pratical Data Acquisition for Instrumentation and Control Systems. Oxford: Elsevier, 2003. ISBN 07506 57960.

RAUSCHENBACH, H. S. Solar array design handbook. New York, Litton Educational Publishing, 1980.

Artigos selecionados de revistas de revistas especializadas.

**CMS-329-4 | Chemical Kinetics****Eletiva**

**Pré-requisito:** não há

**Carga horária:** 60 horas

Basics of chemistry, concept of the thermodynamic properties of the mixtures. First and second law for mixtures. Chemical equilibrium. Thermodynamic functions from the point of view of the kinetic theory of gases. Simple and multiple reactions. Reaction speed. Calculation of the constant reaction of the kinetic theory of gases. Reactions in condensed phases. Types of chemical reactors and their characteristics. Complex reactions and reduced kinetics.

**Blibiografia**

MISSEN, R. W; MIMS, C. A.; SAVILLE, B. A. Introduction to Chemical reaction Engineering and Kinetics. John Wiley & Sons, Inc., 1999.

MONCRIEF, J. W. Elements of Physical Chemistry, Addison Wesley Publishing Company, 1977.

DENBIGH, K. G. The Principles of Chemical Equilibrium: With Applications in Chemistry and Chemical Engineering, Cambridge University Press, 1981.

**CMS-336-4 | Mechanical characterization of materials****Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Fundamentals of materials resistance. Materials for structural applications: mechanical properties of metallic, ceramic and polymeric materials. Stress and strain curve. Fundamentals of fracture, ductile and brittle fracture. Conventional mechanical testing of materials: traction, tensile, tests related to fragile fracture, hardness testing, fatigue test. Mechanical tests of metallic materials, ceramic materials (Weibull statistics), polymeric materials and composite materials. Mechanical characterization of materials in temperatures above the environment.  
Note: The discipline is divided into theoretical classes and laboratory practices.

**Bibliografia**

BUDINSKI, K.; BUDINSKI, M. Engineering Materials, Properties and Selection, 6<sup>th</sup> ed., Prentice-Hall Inc., 1999.

CALLISTER JR, W. Materials Science and Engineering an Introduction. John Wiley and Sons, 1999.

SMITH, W. F. Princípios de Ciência e Engenharia dos Materiais., 3<sup>a</sup> ed., McGraw-Hill, Portugal, 1998.

SHAH, V. Handbook of Plastics Testing Technology, 2<sup>a</sup> ed. John Wiley and Sons, 1998.

ANDERSO, J. C. et ali. Materials Science, 4<sup>a</sup> ed. Chapman & Hall, 1991.

EVANS, R.W.; WILSHIRE, B. Introduction to Creep, The Institute of Materials, London, 1993.

GARCIA, A.; ALVARES, J.; ALEXANDRE, C. Ensaios de Materiais, LTC Editora, Rio de Janeiro, 2000.

SOUZA, C. L. Ensaios Mecânicos de Materiais Metálicos. Editora Edgard Blücher Ltda., São Paulo, 1982.

Selected papers.

#### **CMS-337-4 | Introduction to nanoscience and nanotechnology of materials**

##### **Obrigatória adicional**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

The Nanometric universe. Definitions of nanoscience and nanotechnology. Scientific and technological importance: advantages and limitations. Introduction to Nanomaterials: Atomic structure, nanostructures, defects, thermodynamics, surfaces and interfaces. Introduction to the physics and chemistry of nanomaterials. Molecular nanotechnology. Nanopowders. Nanotubes. Nanofilms. Nanocomposites. Nanoelectronics. Nanocomputers. Fuel cells. Nanomaterials in environmental recovery. Nanotechnology in medicine. Nanotechnology in the areas for aeronautics and space applications. Legal and ethical considerations.

##### **Bibliografia**

HU, S. E.; ROCO, M. C. Nanostructure Science and Technology: A Worldwide Study. National Science and Technology Council (NSTC), Maryland, USA, 1999.

BRUECK, S. J. et all. Implications of Emerging Micro-and Nanotechnologies. National Academies Press, Washington, 2003.

BACHMANN, G. et all. Applications of Nanotechnology in Space Developments and Systems. Future Technologies, n 47. VDI Technology Center, Germany, 2003.

TOMA, H. E. O Mundo Nanométrico: A Dimensão do Novo Século. Livraria Politécnica Ltda., São Paulo, 2004.

BRUSHAN, B. (editor). Springer Handbook of Nanotechnology. Springer, 2004.

GOLDSTEIN, A. N. (editor). Handbook of Nanophase Materials. Marcel Dekker, Inc., New York, NY, USA, 1997.

THEODORE, L. Nanotechnology: Basic Calculations for Engineers and Scientists. Wiley & Sons, Inc., Hoboken, NJ, USA, 2006.

Selected papers.

#### **CMS-347-4 | Introduction to Radiometry**

##### **Eletiva**

**Pré-requisito:** não há

**Carga horária:** 60 horas

Introduction to the basic concepts of radiometry and photometry and their applications. Electromagnetic spectrum. Laws of radiometry and photometry. Propagation of electromagnetic radiation in optical systems. Optical properties of materials. Aberrations in optical systems, sources of Radiation (e.g.: black body, filament lamps, fluorescent lamps, gas discharge, LED, laser, plasma and sun). Radiation detectors (e.g.: thermopile, photomultipliers, photodiodes and CCD). Optical systems used in laboratories (monochromator, integrating sphere, solar simulators, angular and spectral sensor response measure). calibration and laboratory activities.

**Bibliografia**

McCLUNEY, R. Introduction to Radiometry and Photometry.  
PALMER, J. M.; GRANT, B. G. The Art of Radiometry.

<b>CMS-403-4</b>	<b>Materials surfaces and Interfaces: modification and characterization</b>
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**Eletiva**

**Pré-requisito:** CMS-307-4 ou equivalente

**Carga horária:** 60 horas

Scientific and technological importance. Types of surfaces and interfaces. Main features, advantages and limitations. Modifications of chemical surfaces, thermochemical, electrochemical, mechanical, thermomechanical and conventional vaporization, sputtering, electron beam, laser, plasmas (nitriding, carburizing, nitro-carburizing, boriding, carbo- boriding, nitro- boriding, plasma jet, ion planting, PVD, CVD) and implantation of ions (by ion beam, plasma immersion implantation and ion mixing). Chemical characterization of surfaces and interfaces. Physical characterization of surfaces and interfaces. Analysis of phases and states of mechanical tensions on surfaces and interfaces. Analysis of the parameters of mechanical properties.

**Bibliografia**

BURAKOWSKI, T.; WIERZCHON, T. Surface Engineering of Metals: Principles, Equipments and Technologies. CRC Press, New York, 1999.  
OHRING, M. The materials science of thin films. Academic Press, USA, 1991.  
MASEL, R. I. Principles of Adsorption and Reaction on Solid Surfaces. John Wiley & Sons Inc., 1<sup>st</sup> edition, U.S.A., 1996.  
LUTH, H. Surfaces and interfaces of solid materials. Pergamon Press Inc., New York, 1998.  
SUTTON, A. P.; BALLUFFI, R. W. Interfaces in Crystalline Materials, Oxford University Press, Oxford, 1996.  
BROOKS, C. R. Principles of the Surface Treatment of Steels. Technomic Publishing Co. Inc., U.S.A., 1992.  
WILSON, S.; BRUNICLE, C. R.; EVANS, C. Encyclopedia of Materials Characterization: Surfaces, Interfaces, Thin Films. Willey & Sons, New York, 1992.  
BURAKOWSKI, T.; WIERZCHON, T. Surface Engineering of Metals. CRC Press, New York, 1999.  
Handbook of Metals, vol. 10, 9<sup>th</sup>. edition, 1986.  
Selected papers.

<b>CMS-404-4</b>	<b>Thin films technology</b>
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**Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Scientific and technological importance. Kinetic Theory of gases. Introduction to vacuum technology. Types of substrate surfaces. Techniques for the preparation and cleaning of substrate surfaces. Thin film growth techniques. Nucleation and film growth mechanisms. Formation of interfaces. Techniques of mechanical, chemistry, electrochemical and optical characterization of thin films.

**Bibliografia**

OHRING, M. The Materials Science of Thin Films. Academic Press., Inc., San Diego, U.S.A, 1991.  
CALISTER Jr., W. D. Materials Science and Engineering - An Introduction. John Wiley & Sons Inc., 3<sup>rd</sup> edition, U.S.A., 1994.  
PULKER, H. K. et al. Wear and Corrosion Resistant Coatings by CVD and PVD. Expert Verlag, Suécia, 1989.

Handbook of Metals, vol. 10, 9<sup>th</sup> edition, 1986.  
Selected papers.

#### **CMS-405-4 | CVD Diamond Film Growth**

##### **Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Introduction: Diamond properties and structure, surface structure. History of low-pressure diamond growth. CVD Diamond growth methods: hot filament, non-isothermal plasma, thermal plasmas, combustion. CVD diamond growth process: chemical kinetics of gaseous phase, growth models, Bachman's ternary diagram, growth mechanisms. Dependence on growth parameters. Characterization Methods of CVD Diamond. Recent and planned applications for Diamond CVD: mechanical, optical, dental, microelectronics, heat dissipation, etc.

##### **Bibliografia**

SPEAR, K. E.; DISMUSKES, J. P. Synthetic Diamond: Emerging CVD Science and Technology. John Wiley & Sons, New York, 1994.

Recent articles in the field.

#### **CMS-406-4 | Porous materials**

##### **Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Definition of porous and nanoporous materials. Pore structure. Interconnecting pores and surface area. Capillary in porous media. Adsorption and absorption in gas-solid and solid-liquid interfaces. Reactivity on solid surfaces. Techniques for the manufacture of porous and nanoporous materials. Characterization techniques.

##### **Bibliografia**

ROUQUEROL, F.; ROUQUEROL, J.; SING, K. Adsorption by Powders and Porous Solids : Principles, Methodology and Applications. Academic Press Inc., 1998.

DULLIEN, F. A. L. Porous Media : Fluid Transport and Pore Structure. 2<sup>nd</sup> edition, Academic Press Inc., Boston, 1997.

LICHTNER, P. C. Reactive Transport in Porous Media. Mineralogical Society of America, USA, 1996.

TRÜMMLER; R. OBERACKER, A. An Introduction to Powder Metallurgy. The Institute of Materials, 1 Carlton House Terrace, London, 1993.

RING, T. A. Fundamentals of Ceramic Powder Processing. Academic Press Inc., 1996.

#### **CMS-407-4 | Covalent ceramics and aerospace applications**

##### **Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Types of covalent ceramics. Covalent composites. Synthesis of silicon nitride, silicon carbide and boron carbide powders. Silicon nitride matrix reinforced with silicon carbide particles, silicon carbide whiskers and silicon carbide fibers. Nanocomposites of structural covalent ceramics. Fluency and tenacity to the fracture of silicon nitride.

**Bibliografia**

SÔMIYA, S. INOMATA, Y. (Ed.). Silicon carbide ceramics - 2: gas phase reactions, fibrers and whisker, joining. London: Elsevier Applied Science (Ceramic Research and development in Japan Series), 1991.

KINGERY, W. D. Introduction to Ceramics. New York: John Wiley & Sons, 1960.

REED, J. S. Introduction to the principles of ceramic processing. New York: John Wiley & Sons, 1988.

**CMS-409-4 Environmental sensors and control****Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Principles of detection and monitoring of physical and chemical parameters. Basic electrical circuits and detection principles. Electromagnetic radiation sensors. Temperature sensors. Pressure, sound and mechanical deformation sensors. Chemical sensors (gases and liquids). Humidity sensors. Other.

**Bibliografia**

MIDDELHOEK, S.; IAWANSSON, K.; SINAPIUS, G.; HOORNAERT, W. (editors). Handbook of Sensors and Actuators (series). Elsevier Science B.V., 1999.

SINCLAIR, I. R. Sensors and Transducers – A guide to technicians, second edition, Butterworth-Heinemann Ltd, 1992.

DE SILVA, C. W. Control Sensors and Actuators, Prentice-Hall Inc., 1989.

SEIPPEL, R. G. Transducers, Sensors and Detectors, Reston Publishing Company Inc., 1983. Selected papers.

**CMS-410-4 Plasma Technology for surface treatment****Eletiva**

**Pré-requisito:** não há

**Carga horária:** 60 horas

The course consists of five separate modules, described below:

-Basic plasma concepts: concepts and definitions of plasma discharge parameters.

-Plasma sources: plasma discharges produced by different sources (DC luminescent, arc, radio frequency, microwave).

-Plasma Diagnostics: most used techniques to obtain relevant plasma parameters, with emphasis on electrostatic probes and optical emission spectroscopy.

-Plasma Surface treatment processes: The peculiarities and applications of different plasma surface treatment processes, plasma immersion ion implantation, nitriding and obtaining of DLC.

-Application of a treatment method in materials: experimental activity for surface treatment of polished samples, by one of the plasma processes described in the course.

**Bibliografia**

HUTCHINSON, I. H. Principles of Plasma Diagnostics. Cambridge University Press – 2<sup>nd</sup> Edition, 2002.

CHEN, F. F. Introduction to Plasma Physics and Controlled Fusion. Springer – 1<sup>st</sup> Edition, 1995.

ANDERS, A. Handbook Of Plasma Immersion Ion Implantation And Deposition. John Wiley & Sons, 1<sup>st</sup> edition, 2000.

## **CMS-414-4 Advanced ceramics processing and characterization**

### **Eletiva**

**Pré-requisito:** CMS-306-4 ou equivalente

**Carga horária:** 60 horas

Scientific and technological importance. General concepts of processing of ceramics from powders. Comminution and classification of ceramic powders. Powder synthesis. Other processes for powder production. Powder characterization. Ceramics forming: dry and humid. Sintering. Characterization of sintered ceramics. Final finish. Non-destructive tests.

### **Bibliografia**

RING, T. A. Fundamentals of Ceramic Powder Processing and Synthesis. Academic Press Inc., San Diego, U.S.A., 1996.

REED, J. S., Introduction to the Principles of Ceramic Processing, John Wiley & Sons, 1991.

SCHWARTZ, M. Handbook of Structural Ceramics. Academic Press Inc., New York, 1998.

Selected papers.

## **CMS-415-4 Processing and characterization of nanostructured ceramics**

### **Eletiva**

**Pré-requisito:** CMS-306-4 ou equivalente

**Carga horária:** 60 horas

Scientific and technological importance. General concepts of processing of ceramics from powder. Definition of nanoparticles, physical and chemical characteristics. Techniques of obtaining: physical, mechanical and chemical. Techniques of physical and chemical characterization. Ceramics forming: dry and humid. Sintering. Characterization of sintered ceramics. Analysis, interpretation and correlation of experimental results.

### **Bibliografia**

YING, J. Y.-R.; YING, J. Nanostructured Materials. Academic Press Inc., U.S.A., 2001.

WANG, Z. L. Characterization of Nanophase Materials. Wiley-VCH Verlag, Alemanha, 2001.

WASEDA, Y.; MURAMATSU, A. Morfology control of materials and nanoparticles: advanced materials processing and characterization. John Wiley & Sons, USA, 2004.

SCHMID, G. Nanoparticles: from theory to application. John Wiley & Sons, USA, 2004.

RING. T. A. Fundamentals of Ceramic Powder Processing and Synthesis. Academic Press Inc., San Diego, U.S.A., 1996.

HENCH, L.; ULRICH, D. R. Ceramic chemical processing. John Wiley & Sons, USA, 1986.

MAKENZIE, J. D.; ULRICH, D. R. Ultrastructure processing of advanced ceramics. John Wiley & Sons, USA, 1988.

Artigos de periódicos especializados.

## **CMS-416-4 Nanoparticle powder: Obtaining, characterization and applications**

### **Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Importance of the science and technology of nanoparticles. Definition of nanoparticles, physical and chemical characteristics. Nanoparticle powders (nanopowders) and flocculation, agglomeration and aggregation mechanisms. Techniques of obtaining nanopowders: physical, mechanical and chemical. Main techniques for obtaining powders and ceramic and metallic nanoparticle compounds by chemical methods. The importance of conventional and microwave thermal treatments. Obtaining nanoparticle chemical compounds by mechanical allowing. Techniques of physical and chemical characterization of nanoparticle powders (ATD-ATG, Porosimetry, BET, X-ray diffraction, particle size distribution, SEM, TEM, FEG-SEM, EDS,

XPS). Analysis, interpretation and correlation of experimental results (real case studies). Applications.

**Bibliografia:**

- WASEDA, Y.; MURAMATSU, A. Morfology Control of Materials and Nanoparticles: Advanced Materials Processing and Characterization. John Wiley & Sons, USA, 2004.
- FENDLER, J. H. Nanoparticles and Nanostructured Films: Preparation, Characterization and Applications. Wiley-VCH Verlag, Weinheim, Germany, 1998.
- SCHMID, G. Nanoparticles: from theory to application. John Wiley & Sons, USA, 2004.
- RAO, C. N. R.; MÜLLER, A.; CHEETHAM, A. K. (Editors). The Chemistry of Nanomaterials: Synthesis, Properties and Applications. John Wiley & Sons, USA, 2004.
- WINTERER, M. Nano-crystalline Ceramics: Synthesis and Strucuture. Spring-Verlag, Berlin, Germany, 2002.
- FREER, R. Nanoceramics. Institute of Materials, Manchester, England, 1993.
- THEODORE, L. Nanotechnology: Basic Calculations for Engineers and Scientists. Wiley & Sons, Inc., Hoboken, NJ, USA, 2006.
- GOLDSTEIN, A. N. (editor). Handbook of Nanophase Materials. Marcel Dekker, Inc., New York, NY, USA, 1997.
- BRUSHAN, B. (editor). Springer Handbook of Nanotechnology. Springer, 2004.
- MAKENZIE, J.D.; ULRICH, D.R. Ultrastructure processing of advanced ceramics. John Wiley & Sons, USA, 1988.
- Selected papers.

**CMS-417-4 | Nanostructured films: Obtaining, characterizing and applications**

**Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Nanostructured Ceramic and Metallic films: Scientific and technological importance: advantages and limitations. Techniques for the preparation of adherent polycrystalline films (chemical and physical). Surface and interface characterization techniques (X-ray diffraction, electron scanning microscopy, transmission electron microscopy, atomic force microscopy, Raman spreading spectroscopy, dispersive energy spectrometry, Auger electron spectroscopy, photoelectron X-ray spectroscopy, adhesion measurements, nanohardness and fracture tenacity. Main applications of these types of films.

Nanostructured Carbon-based films: Scientific and technical importance: advantages and limitations. Obtaining, characterization and applications. Carbon fibers, reticulated vitreous carbon, nanostructured graphite. Carbon nanotubes, DLC films and hydrogenated DLC. NanoDiamond Films. Raman spreading spectroscopy and X-ray diffraction techniques.

Nanostructured films of semiconductor compounds IV-VI: Scientific and technological importance: advantages and limitations. Epitaxial growth techniques. Fundamental aspects of epitaxy by molecular Beam (MBE). Growth Properties. Heterostructures. Dots and quantum pits. Super nets. Multiple self structures.

**Bibliografia**

- FENDLER, J. H. Nanoparticles and Nanostructured Films: Preparation, Characterization and Applications. Wiley-VCH Verlag, Weinheim, Germany, 1998.
- BRUSHAN, B. (editor). Springer Handbook of Nanotechnology. Springer, 2004.
- GOLDSTEIN, A. N. (editor). Handbook of Nanophase Materials. Marcel Dekker, Inc., New York, NY, USA, 1997.
- THEODORE, L. Nanotechnology: Basic Calculations for Engineers and Scientists. Wiley & Sons, Inc., Hoboken, NJ, USA, 2006.
- BENEDEK, G. et al. (Editors). Nanostructured Carbon for Advanced Applications. NATO Science Series II: Mathematics, Physics and Chemistry, Volume 24. 1<sup>st</sup> edition. Springer, 2001.
- Selected papers.

CMS-419-4	Principles of electrochemical
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**Eletiva**

**Pré-requisito:** não há

**Carga horária:** 60 horas

Basic concepts of electrochemical (oxidation, reduction, galvanic and electrolytic systems, electrode standard potential and redox reactions spontaneity), electrodic processes (Faradaics and non-faradaics, electrode/electrolyte interface, reactions controlled by mass transfer), electrochemical kinetic, electro-chemical techniques (potential and current jump, cyclic and linear voltammetry, differential pulse and square wave voltammetry). Electrochemical Impedance (IE) methods, circuit elements, graphical representation (Nyquist, Bode), equivalent circuits (electrochemical), impedance study using the software. Examples of IE for diamond electrodes.

**Bibliografia:**

ATKINS, P., Físico Química – Fundamentos, 3<sup>a</sup> edição, LTC editora, 2001.

BARD, A. J.; FAULKNER, L. R. Electrochemical Methods-Fundaments and Applications. John Wiley & Sons, New York, 1980.

BRETT, C. M. A. Electrochemistry, Principles, Methods, and Applications. Oxford Publications, 2000.

BOCKRIS, J. O. M. Modern Electrochemistry, vol 1, 2A, 2B, Kluwer Academic, 2000.

CMS-420-4	X-ray diffractometry for characterization of crystalline structure of materials
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**Eletiva**

**Pré-requisito:** não há

**Carga horária:** 60 horas

Basic crystallography: unitary cell; Crystalline plans; Interplanar distances; Miller indexes; Crystalline structure; Elements of symmetry and spatial groups; Reciprocal lattice. X-ray diffraction: Introduction to X-ray diffraction theory; Bragg's Law; X-ray Diffractometer; Factors influencing the scattered intensities of x-rays; X-ray generation and detection; Diffractometry of Powder. Experimental practice: Phase identification; database; Peak indexing; Quantitative analysis; Crystallographic guidance; Crystalline structure refinement.

**Bibliografia:**

CULLITY, D. B.; STOCK, S. R. Elements of X-Ray Diffraction. 3rd. ed., Prentice Hall, New Jersey, 2001.

WASEDA, Y.; MATSUBARA, E.; SHINODA, K. X-Ray diffraction crystallography: introduction, examples and solved problems. Springer-Verlag Berlin Heidelberg, 2011.

PECHARSKY, V. K.; ZAVALIJ, P. Y. Fundamentals of powder diffraction and structural characterization of materials, Springer New York, 2005.

X'pert Pro Panalytical user manual.

Selected papers.

CMS-421-4	Introduction to microscopy of materials
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**Eletiva**

**Pré-requisito:** CMS-200-4 ou equivalente

**Carga horária:** 60 horas

Basic theory of microscopy; diffraction images formation; optical microscopy; Scanning Image formation; Electron microscopy (scanning and transmission); other scanning microscopies; Microanalysis, EDS, WDS, EELS, STEM, EPMA; sample preparation for microscopy.

**Bibliografia:**

- MANNHEIMER, W. A. Microscopia dos Materiais. SBMM, 2002.
- GOLDSTEIN, J. et al. Scanning electron microscopy and x-ray microanalysis. 3<sup>rd</sup> Ed., New York: Springer Science + Business Media, Inc., 2003.
- WIESENDANGER, R. Scanning Probe Microscopy and Spectroscopy: Methods and Applications. Cambridge University Press, Cambridge, UK, 1994.
- MEYER, E. et al. Scanning Probe Microscopy: The Lab on a Tip. Springer-Verlag, 2003.
- BRUNDEL, C. R. et al. Encyclopedia of Materials Characterization. Butterworth-Heinemann, 1992.

**DISCIPLINAS DE EMENTA ABERTA DA ÁREA DE CONCENTRAÇÃO EM CIÊNCIA E TECNOLOGIA DE MATERIAIS E SENSORES**

**CMS-315-1 | Special topics in science and physics of materials I**

**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 15 horas

Discipline with appropriate content for each subject.

**CMS-316-2 | Special topics in science and physics of materials II**

**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 30 horas

Discipline with appropriate content for each subject.

**CMS-339-3 | Special topics in science and physics of materials III**

**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 45 horas

Discipline with appropriate content for each subject.

**CMS-340-4 | Special topics in science and physics of materials IV**

**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

**CMS-317-1 | Special topics in materials processing I**

**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 15 horas

Discipline with appropriate content for each subject.

**CMS-318-2 | Special topics in materials processing II**

**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 30 horas

Discipline with appropriate content for each subject.

<b>CMS-341-3</b>	<b>Special topics in materials processing III</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 45 horas

Discipline with appropriate content for each subject.

<b>CMS-342-4</b>	<b>Special topics in materials processing IV</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-319-1</b>	<b>Special topics in materials characterization techniques I</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 15 horas

Discipline with appropriate content for each subject.

<b>CMS-320-2</b>	<b>Special topics in materials characterization techniques II</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 30 horas

Discipline with appropriate content for each subject.

<b>CMS-343-3</b>	<b>Special topics in materials characterization techniques III</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 45 horas

Discipline with appropriate content for each subject.

<b>CMS-344-4</b>	<b>Special topics in materials characterization techniques IV</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-324-4</b>	<b>Research in physics of materials I</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-325-4</b>	<b>Research in physics of materials II</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-326-4</b>	<b>Research in physics of materials III</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-330-4</b>	<b>Research in physics of materials IV</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-331-4</b>	<b>Research in physics of materials V</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-332-4</b>	<b>Research in physics of materials VI</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-345-4</b>	<b>Research in physics of materials VII</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-321-4</b>	<b>Research in science and technology of materials I</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-327-4</b>	<b>Research in science and technology of materials II</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-328-4</b>	<b>Research in science and technology of materials III</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-333-4</b>	<b>Research in science and technology of materials IV</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-334-4</b>	<b>Research in science and technology of materials V</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-335-4</b>	<b>Research in science and technology of materials VI</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

<b>CMS-346-4</b>	<b>Research in science and technology of materials VII</b>
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**Eletiva**

**Pré-requisito:** a definir de acordo com a ementa

**Carga horária:** 60 horas

Discipline with appropriate content for each subject.

**Os trabalhos auxiliares ou finais do programa de pós-graduação serão identificados nas formas abaixo indicadas:**

<b>CMS-730</b>	<b>Pesquisa de Mestrado em Engenharia e Tecnologia Espaciais/CMS*</b>
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**Obrigatória**

**Crédito: 0**

<b>CMS-750</b>	<b>Dissertação de Mestrado em Engenharia e Tecnologia Espaciais/CMS</b>
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**Obrigatória**

**Créditos: 12**

<b>CMS-780</b>	<b>Pesquisa de Doutorado em Engenharia e Tecnologia Espaciais/CMS*</b>
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**Obrigatória**

**Crédito: 0**

<b>CMS-800</b>	<b>Tese de Doutorado em Engenharia e Tecnologia Espaciais/CMS</b>
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**Obrigatória**

**Crédito: 36**

\* Atividade *Obrigatória*, em cada período letivo, para todo aluno em fase de Pesquisa, definida pela oficialização de seu Orientador de Pesquisa que avaliará o desempenho do aluno nesta atividade. *Obrigatória*, também, antes da oficialização citada, para o aluno que não esteja matriculado em alguma disciplina: neste caso, a orientação e a avaliação deverão ser feitas por Docente aprovado pelo Coordenador Acadêmico.

Catálogo aprovado pelo CPG em 15/02/2019.